Application/Control No.	Applicant(s)/Patent under Reexamination
10/660,698	OHISHI ET AL.
Examiner	Art Unit
Fikremariam Yalew	2136

SEARCHED							
		<u> </u>					
Class	Subclass	Date	Examiner				
380	200	3/30/2007	FA				
713	182	3/30/2007	FA				
			<u> </u>				

INI	ERFERENC	E SEARCH	IED
Class	Subclass	Date	Examiner
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(INCLUDING SEARCH	TES I STRATEGY)
	DATE	EXMR
East(classification search and text search)	3/30/2007	FA
IEEE	3/30/2007	FA
Inventor search	3/30/2007	FA
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